



TFW / AF

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:	§	Attorney Docket No. 24061.470
Cheng, et al	§	2002-0150
	§	
Serial No.: 10/697,833	§	Customer No. 42717
	§	
Filed: October 30, 2003	§	Group Art Unit: 2823
	§	
For: A METHOD OF IMPROVING	§	Examiner: Dang, Trung Q
SHORT CHANNEL EFFECT AND	§	
GATE OXIDE RELIABILITY BY	§	Confirmation No.: 927
NITROGEN PLASMA TREATMENT	§	
BEFORE SPACER DEPOSITION	§	

RESPONSE TO OFFICE ACTION

Mail Stop AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Examiner:

In response to the Final Office Action of February 23, 2005, please consider the following:

Listing of Claims, beginning on page 2 of this paper, provided for the convenience of the Examiner

Remarks beginning on page 9 of this paper.